



Pr. Vincent Goiffon
ISAE-SUPAERO, France

Vincent Goiffon received the Master's degree in Aerospace Engineering (diplome d'Ingénieur) and the Master's degree in EE, both from SUPAERO, in 2005. In 2008, he received his Ph.D. in EE from ISAE-SUPAERO, University of Toulouse. The same year he joined ISAE-SUPAERO as an Associate Professor and he has been a Full Professor of Electronics since 2018. He is currently the Head of the Image Sensor Research Group of the Institute. He has contributed to advance the understanding of radiation effects on solid-state image sensors, notably by identifying original degradation mechanisms in pinned photodiode pixels and by clarifying the role of interface and bulk defects in the mysterious dark current random telegraph signal phenomenon. Besides his contributions to various space R&D projects, Vincent has been leading the development of radiation hardened CMOS image sensors (CIS) and cameras for nuclear fusion experiments (e.g. ITER and CEA Laser MegaJoule) and nuclear power plant safety. Vincent Goiffon is the author of one book chapter and more than 90 scientific publications, including more than 10 conference awards at IEEE NSREC, RADECS and IISW. He has been an associate editor of the IEEE Transactions on Nuclear Science since 2017 and has served the community as reviewer and session chair.